



## Description

The IRFB4410PBF use advanced SGT MOSFET technology to provide low  $R_{DS(ON)}$ , low gate charge, fast switching and excellent avalanche characteristics. This device is specially designed to get better ruggedness and suitable.

## General Features

$V_{DS} = 100V$   $I_D = 70A$

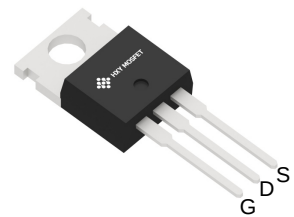
$R_{DS(ON)} < 10.5m\Omega @ V_{GS}=10V$

## Application

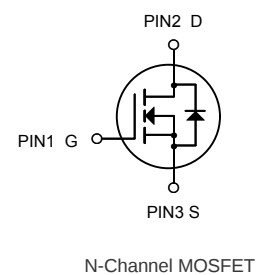
Battery protection

Load switch

Uninterruptible power supply



TO-220C



## Package Marking and Ordering Information

| Product ID  | Pack    | Brand      | Qty(PCS) |
|-------------|---------|------------|----------|
| IRFB4410PBF | TO-220C | HXY MOSFET | 50       |

## Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise noted)

| Symbol               | Parameter                                        | Rating     | Units        |
|----------------------|--------------------------------------------------|------------|--------------|
| $V_{DS}$             | Drain-Source Voltage                             | 100        | V            |
| $V_{GS}$             | Gate-Source Voltage                              | $\pm 20$   | V            |
| $I_D$                | Continuous Drain Current@ $T_C=25^\circ C$       | 70         | A            |
| $I_{DM}$             | Puled Drain Current <sup>1</sup>                 | 280        | A            |
| EAS                  | Single Pulse Avalanche Energy <sup>3</sup>       | 110        | mJ           |
| $P_D@T_C=25^\circ C$ | Total Power Dissipation <sup>4</sup>             | 100        | W            |
| $T_{STG}$            | Storage Temperature Range                        | -55 to 150 | $^\circ C$   |
| $T_J$                | Operating Junction Temperature Range             | -55 to 150 | $^\circ C$   |
| $R_{\theta JA}$      | Thermal Resistance Junction-Ambient <sup>1</sup> | 64         | $^\circ C/W$ |
| $R_{\theta JC}$      | Thermal Resistance Junction-Ambient <sup>1</sup> | 1.25       | $^\circ C/W$ |



**Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

| Symbol                       | Parameter                                      | Conditions                                                   | Min. | Typ.  | Max.      | Unit                  |
|------------------------------|------------------------------------------------|--------------------------------------------------------------|------|-------|-----------|-----------------------|
| $BV_{DSS}$                   | Drain-Source Breakdown Voltage                 | $V_{GS}=0V$ , $I_D=250\mu A$                                 | 100  | ---   | ---       | V                     |
| $\Delta BV_{DSS}/\Delta T_J$ | BVDSS Temperature Coefficient                  | Reference to $25^{\circ}\text{C}$ , $I_D=1\text{mA}$         | ---  | 0.098 | ---       | $V/^{\circ}\text{C}$  |
| $R_{DS(ON)}$                 | Static Drain-Source On-Resistance <sup>2</sup> | $V_{GS}=10V$ , $I_D=20A$                                     | ---  | 8.5   | 10.5      | $m\Omega$             |
|                              |                                                | $V_{GS}=4.5V$ , $I_D=15A$                                    | ---  | 9.5   | 15        | $m\Omega$             |
| $V_{GS(th)}$                 | Gate Threshold Voltage                         | $V_{GS}=V_{DS}$ , $I_D=250\mu A$                             | 1.0  | ---   | 2.5       | V                     |
| $\Delta V_{GS(th)}$          | $V_{GS(th)}$ Temperature Coefficient           |                                                              | ---  | -4.57 | ---       | $mV/^{\circ}\text{C}$ |
| $I_{DSS}$                    | Drain-Source Leakage Current                   | $V_{DS}=80V$ , $V_{GS}=0V$ , $T_J=25^{\circ}\text{C}$        | ---  | ---   | 1         | $\mu A$               |
|                              |                                                | $V_{DS}=80V$ , $V_{GS}=0V$ , $T_J=55^{\circ}\text{C}$        | ---  | ---   | 5         |                       |
| $I_{GSS}$                    | Gate-Source Leakage Current                    | $V_{GS}=\pm 20V$ , $V_{DS}=0V$                               | ---  | ---   | $\pm 100$ | nA                    |
| $R_g$                        | Gate Resistance                                | $V_{DS}=0V$ , $V_{GS}=0V$ , $f=1\text{MHz}$                  | ---  | 0.48  | ---       | $\Omega$              |
| $Q_g$                        | Total Gate Charge (10V)                        | $V_{DS}=50V$ , $V_{GS}=50V$ , $I_D=10A$                      | ---  | 31.3  | ---       | nC                    |
| $Q_{gs}$                     | Gate-Source Charge                             |                                                              | ---  | 3.49  | ---       |                       |
| $Q_{gd}$                     | Gate-Drain Charge                              |                                                              | ---  | 7.63  | ---       |                       |
| $T_{d(on)}$                  | Turn-On Delay Time                             | $V_{DD}=50V$ , $V_{GS}=10V$ ,<br>$R_G=4\Omega$<br>$I_D=10A$  | ---  | 16    | ---       | ns                    |
| $T_r$                        | Rise Time                                      |                                                              | ---  | 10    | ---       |                       |
| $T_{d(off)}$                 | Turn-Off Delay Time                            |                                                              | ---  | 40    | ---       |                       |
| $T_f$                        | Fall Time                                      |                                                              | ---  | 6     | ---       |                       |
| $C_{iss}$                    | Input Capacitance                              | $V_{DS}=50V$ , $V_{GS}=0V$ , $f=1\text{MHz}$                 | ---  | 1368  | ---       | pF                    |
| $C_{oss}$                    | Output Capacitance                             |                                                              | ---  | 451   | ---       |                       |
| $C_{rss}$                    | Reverse Transfer Capacitance                   |                                                              | ---  | 12.9  | ---       |                       |
| $I_S$                        | Continuous Source Current <sup>1,5</sup>       | $V_G=V_D=0V$ , Force Current                                 | ---  | ---   | 70        | A                     |
| $I_{SM}$                     | Pulsed Source Current <sup>2,5</sup>           |                                                              | ---  | ---   | 280       | A                     |
| $V_{SD}$                     | Diode Forward Voltage <sup>2</sup>             | $V_{GS}=0V$ , $I_S=1A$ , $T_J=25^{\circ}\text{C}$            | ---  | ---   | 1.2       | V                     |
| $t_{rr}$                     | Reverse Recovery Time                          | $I_F=10A$ , $dI/dt=100A/\mu s$ ,<br>$T_J=25^{\circ}\text{C}$ | ---  | 103   | ---       | nS                    |
| $Q_{rr}$                     | Reverse Recovery Charge                        |                                                              | ---  | 187   | ---       | nC                    |

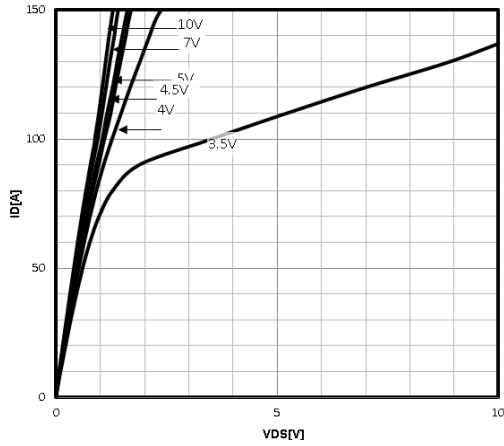
**Note :**

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $V_{DD}=25V$ ,  $V_{GS}=10V$ ,  $L=0.1\text{mH}$ ,  $I_{AS}=11A$
- 4.The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
- 5 .The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

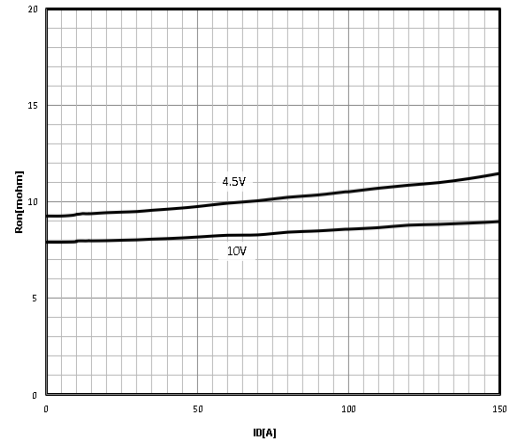


## Typical Characteristics

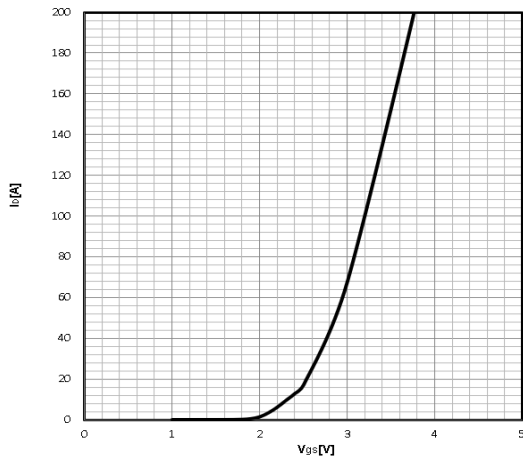
Typ. output characteristics  
 $I_D = f(V_{DS})$



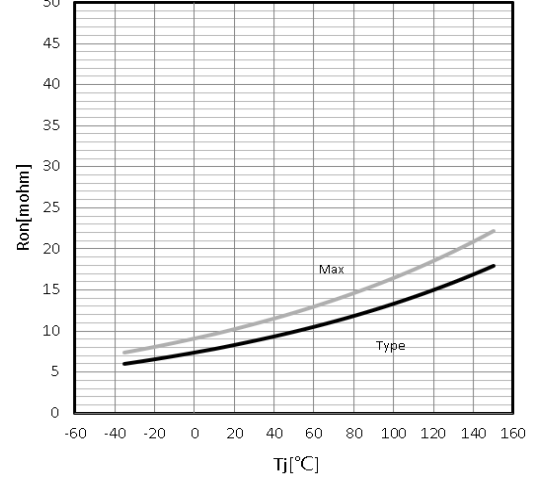
Typ. drain-source on resistance  
 $R_{DS(on)} = f(I_D)$



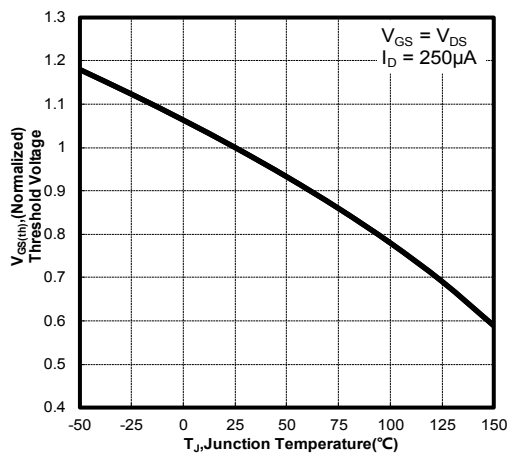
Typ. transfer characteristics  
 $I_D = f(V_{GS})$



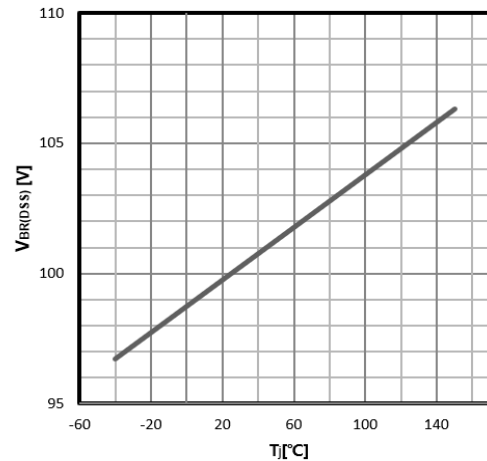
Drain-source on-state resistance  
 $R_{DS(on)} = f(T_J); I_D = 20A; V_{GS} = 10V$



Gate Threshold Voltage  
 $V_{TH} = f(T_J); I_D = 250\mu A$

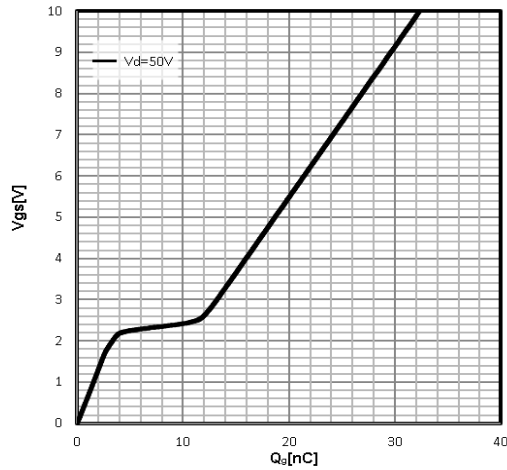


Drain-source breakdown voltage  
 $V_{BR(DSS)} = f(T_J); I_D = 250\mu A$

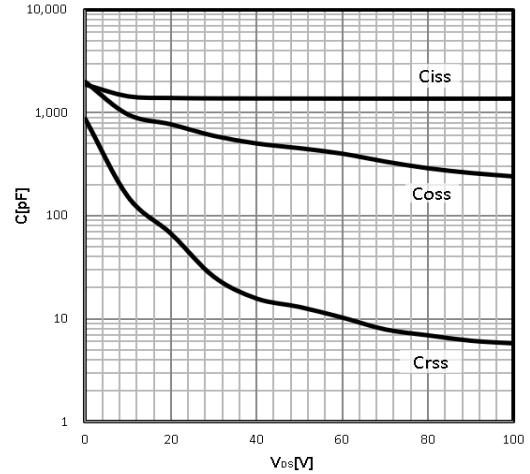




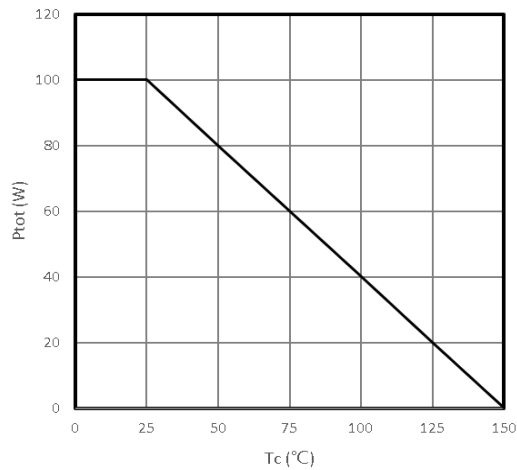
**Typ. gate charge**  
 $V_{GS}=f(Q_g)$ ;  $I_D=10A$



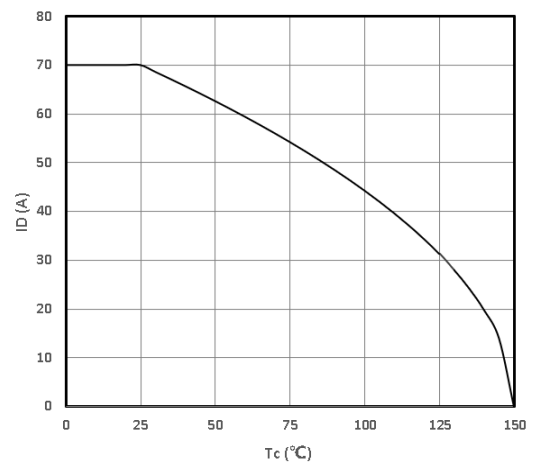
**Typ. capacitances**  
 $C=f(V_{DS})$ ;  $V_{GS}=0V$ ;  $f=1MHz$



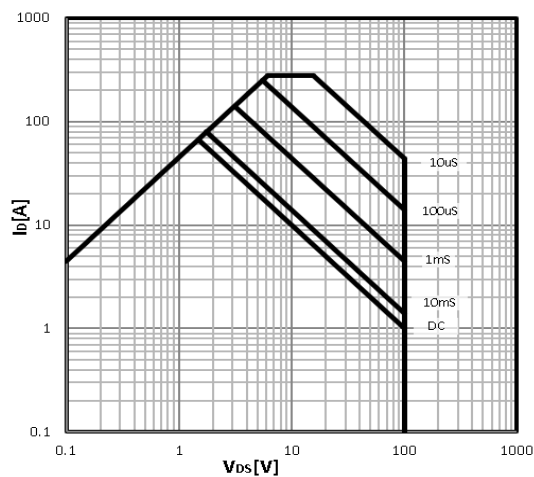
**Power Dissipation**  
 $P_{tot}=f(T_C)$



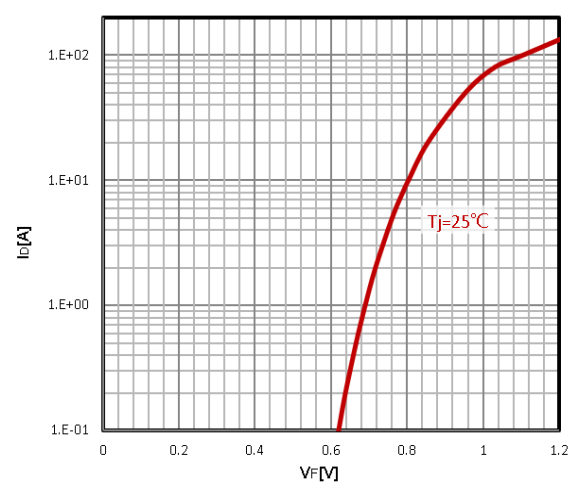
**Maximum Drain Current**  
 $I_D=f(T_C)$



**Safe operating area**  
 $I_D=f(V_{DS})$



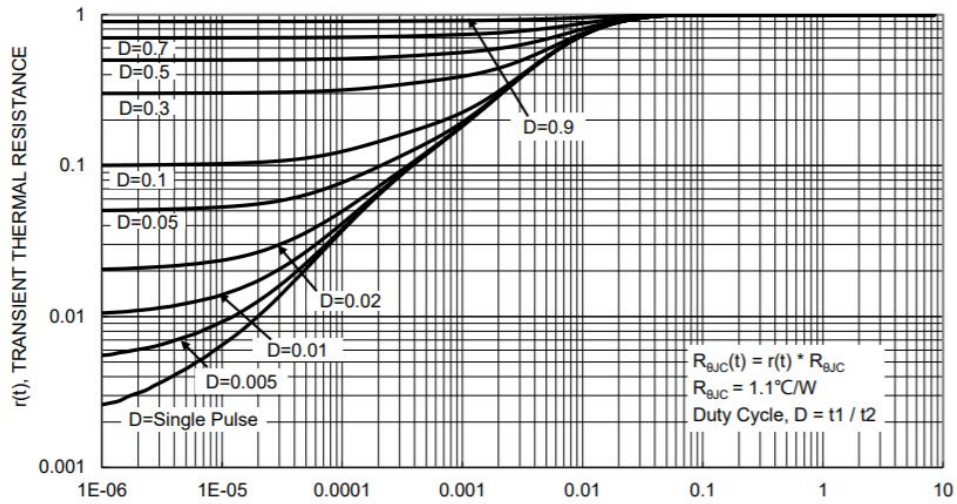
**Body Diode Forward Voltage Variation**  
 $I_F=f(V_{GS})$





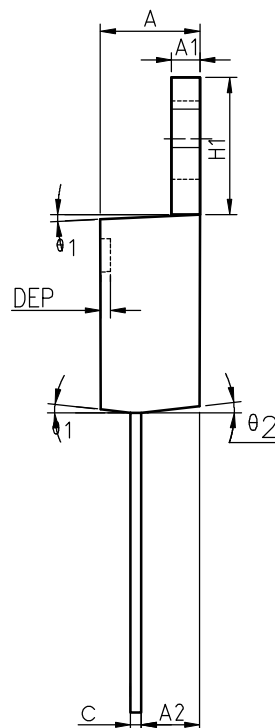
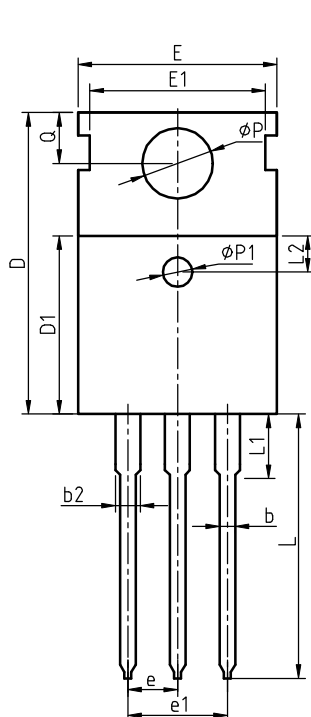
Max. transient thermal impedance

$$Z_{thJC}=f(t_p)$$



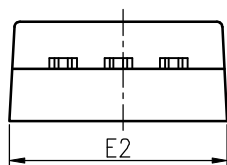


Package Information  
TO-220C



COMMON DIMENSIONS

| SYMBOL  | MIN   | NOM   | MAX   | MIN   | NOM   | MAX   |
|---------|-------|-------|-------|-------|-------|-------|
| A       | 4.40  | 4.57  | 4.70  | 0.173 | 0.180 | 0.185 |
| A1      | 1.27  | 1.30  | 1.33  | 0.050 | 0.051 | 0.052 |
| A2      | 2.35  | 2.40  | 2.50  | 0.093 | 0.094 | 0.098 |
| b       | 0.77  | 0.80  | 0.90  | 0.030 | 0.031 | 0.035 |
| b2      | 1.17  | 1.27  | 1.36  | 0.046 | 0.050 | 0.054 |
| c       | 0.48  | 0.50  | 0.56  | 0.019 | 0.020 | 0.022 |
| D       | 15.40 | 15.60 | 15.80 | 0.606 | 0.614 | 0.622 |
| D1      | 9.00  | 9.10  | 9.20  | 0.354 | 0.358 | 0.362 |
| DEP     | 0.05  | 0.10  | 0.20  | 0.002 | 0.004 | 0.008 |
| E       | 9.80  | 10.00 | 10.20 | 0.386 | 0.394 | 0.402 |
| E1      | -     | 8.70  | -     | -     | 0.343 | -     |
| E2      | 9.80  | 10.00 | 10.20 | 0.386 | 0.394 | 0.402 |
| e       |       | 2.54  | BSC   |       | 0.100 | BSC   |
| e1      |       | 5.08  | BSC   |       | 0.200 | BSC   |
| H1      | 6.40  | 6.50  | 6.60  | 0.252 | 0.256 | 0.260 |
| L       | 12.75 | 13.50 | 13.65 | 0.502 | 0.531 | 0.537 |
| L1      | -     | 3.10  | 3.30  | -     | 0.122 | 0.130 |
| L2      |       | 2.50  | REF   |       | 0.098 | REF   |
| P       | 3.50  | 3.60  | 3.63  | 0.138 | 0.142 | 0.143 |
| P1      | 3.50  | 3.60  | 3.63  | 0.138 | 0.142 | 0.143 |
| Q       | 2.73  | 2.80  | 2.87  | 0.107 | 0.110 | 0.113 |
| theta 1 | 5°    | 7°    | 9°    | 5°    | 7°    | 9°    |
| theta 2 | 1°    | 3°    | 5°    | 1°    | 3°    | 5°    |
| theta 3 | 1°    | 3°    | 5°    | 1°    | 3°    | 5°    |





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